Application/Control No. Applicant(s)/Patent Under Reexamination 10/607,282 SUN ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Theresa Trieu 3748 **U.S. PATENT DOCUMENTS** Document Number Date Country Code-Number-Kind Code Name Classification MM-YYYY * US-4,669,962 Α 06-1987 Mizuno et al. 418/55.5 * US-4,904,164 В 02-1990 Mabe et al. 417/310 C US-5,236,316 08-1993 lio, Takayuki 417/310 * D US-5,356,271 10-1994 Miura et al. 417/310 * Е US-5,993,171 11-1999 Higashiyama, Akiyoshi 417/310 US-F US-G US-Н US-1 US-J K US-US-L US-М FOREIGN PATENT DOCUMENTS Document Number Date Country Name Country Code-Number-Kind Code MM-YYYY Classification JP 63212789 A Ν 09-1988 Japan SATO, TADATSUGU F04C 18/02 JP 01106990 A 0 04-1989 Japan DOI et al. F04C 18/02 Ρ JP 04287888 A 10-1992 Japan MATSUMOTO et al. F04C 18/02 Q R S Ŧ **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W Х

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.